August 2003



FDP6030L/FDB6030L

N-Channel Logic Level PowerTrench^o MOSFET

General Description

This N-Channel Logic Level MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

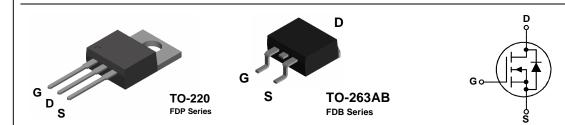
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $R_{\text{DS(ON)}}$ specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

It has been optimized for low gate charge, low $R_{\text{DS}(\text{ON})}$ and fast switching speed.

Features

- 48 A, 30 V $R_{DS(ON)} = 13 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 17 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$
- Critical DC electrical parameters specified at elevated temperature
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- 175°C maximum junction temperature rating



Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V _{DSS}	Drain-Source Voltage	30	V
V _{GSS}	Gate-Source Voltage	± 20	V
ID	Drain Current – Continuous (Note 1)	48	А
	– Pulsed	150	
P _D	Total Power Dissipation @ $T_c = 25^{\circ}C$	52	W
	Derate above 25°C	0.3	W/°C
T _J , T _{STG}	Operating and Storage Junction Temperature Range	-65 to +175	°C

Thermal CharacteristicsReJCThermal Resistance, Junction-to-Case2.9°C/WReJAThermal Resistance, Junction-to-Ambient62.5

Package Marking and Ordering Information

	Device Marking	Device	Reel Size	Tape width	Quantity
	FDB6030L	FDB6030L	13"	24mm	800 units
_	FDP6030L	FDP6030L	Tube	n/a	45

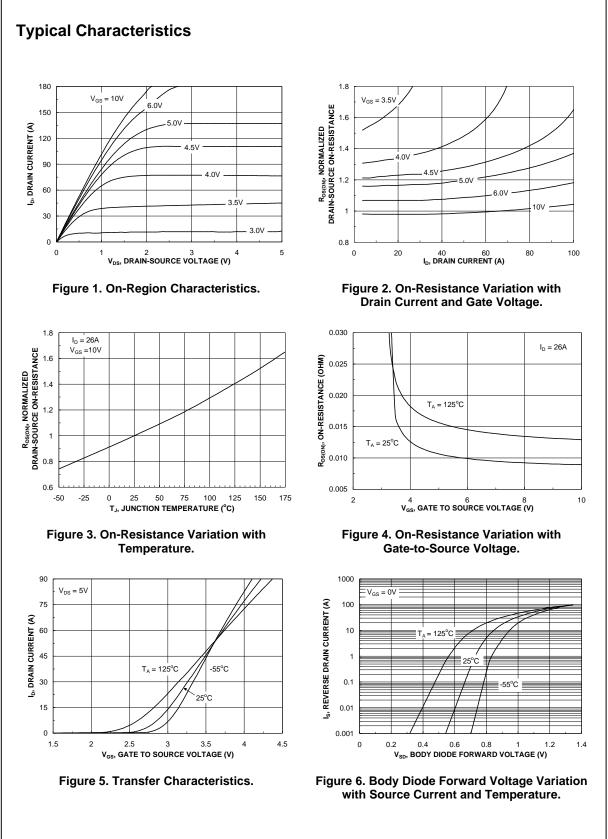
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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	Durce Avalanche Ratings (Note	21)				
E _{AS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 15 \text{ V}, I_D = 26 \text{ A}$			100	mJ
I _{AS}	Maximum Drain-Source Avalanche				26	A
Off Char	Current acteristics					
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{1} = 0 V_{1} = 250 \mu$	30			V
ΔBV_{DSS}	Breakdown Voltage Temperature	$V_{GS} = 0 \text{ V}, \qquad I_D = 250 \mu\text{A}$ $I_D = 250 \mu\text{A}, \text{ Referenced to } 25^\circ\text{C}$	30	23		w mV/°C
<u>ΔT</u> J	Coefficient Zero Gate Voltage Drain Current	$V_{DS} = 24 V$, $V_{GS} = 0 V$			1	
	Gate-Body Leakage	$V_{DS} = 24 V, V_{GS} = 0 V$ $V_{GS} = \pm 20 V, V_{DS} = 0 V$			± 100	μA nA
	, ,	$v_{\rm GS} = \pm 20$ v, $v_{\rm DS} = 0$ v	1		± 100	
	acteristics (Note 2)			4.0	<u> </u>	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, \qquad I_D = 250 \ \mu A$	1	1.9	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$, Referenced to 25°C		-5		mV/°C
R _{DS(on)}	Static Drain–Source On–	$V_{GS} = 10 \text{ V}, I_D = 26 \text{ A}$		7.9	13	
	Resistance	$V_{GS} = 4.5 V$, $I_D = 21 A$		10.2	17	mΩ
	On–State Drain Current	V_{GS} = 10 V, I_D = 26 A, T_J =125°C V_{GS} = 10 V, V_{DS} = 10 V	60	13.0	20	A
D(on)	Forward Transconductance	$V_{\rm ds} = 10 V,$ $V_{\rm Ds} = 10 V$ $V_{\rm Ds} = 10 V,$ $I_{\rm D} = 26 \text{ A}$	00	68		S
g _{FS}		$v_{DS} = 10v$, $i_D = 20 A$		00		5
	Characteristics			10-0		_
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$		1250		pF
Coss	Output Capacitance	f = 1.0 MHz		330		pF
C _{rss}	Reverse Transfer Capacitance			155		pF
R _G	Gate Resistance	$V_{\text{GS}} = 15 \text{ mV}, f = 1.0 \text{ MHz}$		1.3		Ω
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn–On Delay Time	$V_{DD} = 15V, \qquad I_D = 1 \text{ A},$		11	20	ns
tr	Turn–On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		12	22	ns
t _{d(off)}	Turn–Off Delay Time	7		29	46	ns
t _f	Turn–Off Fall Time	7		12	21	ns
Qg	Total Gate Charge	$V_{DS} = 15 V$, $I_D = 26 A$,		13	18	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$		3.9		nC
Q _{gd}	Gate–Drain Charge			5.2		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
I _S	Maximum Continuous Drain–Source				48	Α
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$, $I_S = 26 A$ (Note 1)		0.92	1.3	V
t _{rr}	Diode Reverse Recovery Time	I _F = 26 A,		26		nS
Q _{rr}	Diode Reverse Recovery Charge	$I_F = 26 \text{ A},$ $d_{iF}/d_t = 100 \text{ A}/\mu\text{s}$		15		nC

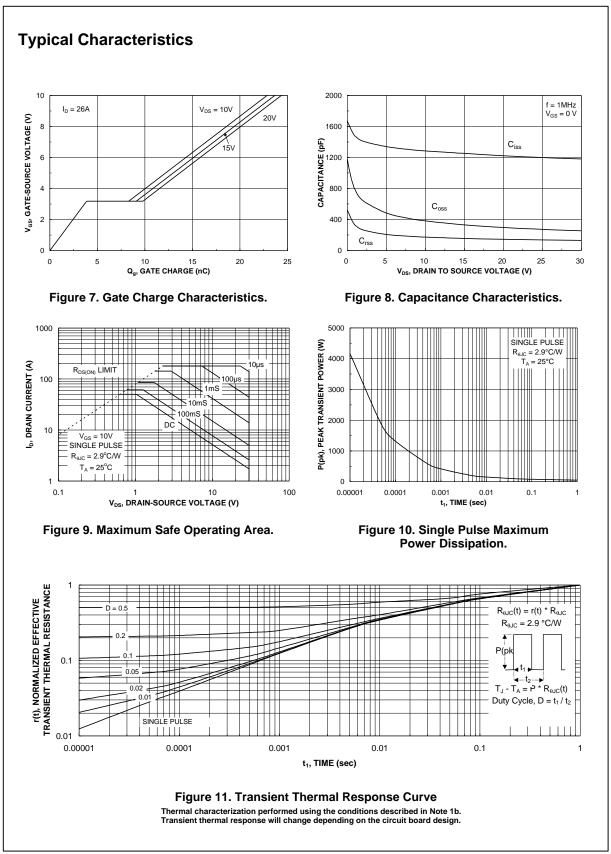
1. Calculated continuous current based on maximum allowable junction temperature.

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

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